

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,020	RAPCHAK	
Examiner	Art Unit	
Anh V. La	2636	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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